



First Semiconductor

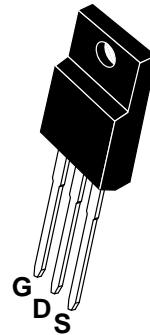
FIR8N80FG

Advanced N-Ch Power MOSFET

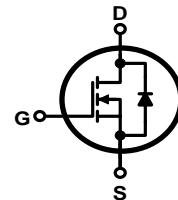
Features

- Low Intrinsic Capacitances
- Excellent Switching Characteristics
- Extended Safe Operating Area
- Unrivalled Gate Charge : $Q_g = 27\text{nC}$ (Typ.)
- $\text{BVDSS}=800\text{V}, \text{ID}=7.5\text{A}$
- $R_{DS(on)} : 1.9 \Omega$ (Max) @ $\text{VG}=10\text{V}$
- 100% Avalanche Tested

PIN Connection TO-220F



Schematic diagram



Marking Diagram



Y = Year
 A = Assembly Location
 WW = Work Week
 FIR8N80F = Specific Device Code

Absolute Maximum Ratings $T_c=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FIR8N80FG	Units
V_{DSS}	Drain-Source Voltage	800	V
I_D	Drain Current -continuous ($T_c=25^\circ\text{C}$)	7.5*	A
	-continuous ($T_c=100^\circ\text{C}$)	4.8*	A
V_{GS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Plused Avalanche Energy (Note1)	380	mJ
I_{AR}	Avalanche Current (Note2)	6.6	A
P_D	Power Dissipation ($T_c=25^\circ\text{C}$)	62	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 ~ +150	°C
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	Parameter	Typ.	Max	Units
$R_{\theta JC}$	Thermal Resistance,Junction to Case	--	2.01	°C/W
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	--	120	°C/W

*Drain current limited by maximum junction temperature.



Electrical Characteristics $T_c=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Condition	Min.	Typ.	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250 \mu\text{A}, \text{VGS}=0$	800	--	--	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$\text{ID}=250 \mu\text{A}, \text{Reference to } 25^\circ\text{C}$	--	0.77	--	$\text{V}/^\circ\text{C}$
IDSS	Zero Gate Voltage Drain Current	$\text{Vds}=800\text{V}, \text{Vgs}=0\text{V}$	--	--	10	μA
		$\text{Vds}=640\text{V}, \text{Tc}=125^\circ\text{C}$			100	μA
IGSSF	Gate-body leakage Current, Forward	$\text{Vgs}=+30\text{V}, \text{Vds}=0\text{V}$	--	--	100	nA
IGSSR	Gate-body leakage Current, Reverse	$\text{Vgs}=-30\text{V}, \text{Vds}=0\text{V}$	--	--	-100	nA

On Characteristics

$\text{V}_{\text{GS(th)}}$	Date Threshold Voltage	$\text{Id}=250\mu\text{A}, \text{Vds}=\text{Vgs}$	3	--	5	V
$\text{R}_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$\text{Id}=3.5\text{A}, \text{Vgs}=10\text{V}$	--	--	1.9	Ω

Dynamic Characteristics

Ciss	Input Capacitance	$\text{VDS}=25\text{V}, \text{VGS}=0, f=1.0\text{MHz}$	--	1420	2060	pF
Coss	Output Capacitance		--	150	195	pF
Crss	Reverse Transfer Capacitance		--	19	25	pF

Switching Characteristics

TD(on)	Turn-On Delay Time	$\text{VDD}=400\text{V}, \text{ID}=3\text{A}$ $\text{RG}=25\Omega$ (Note 3,4)	--	35	80	nS
Tr	Turn-On Rise Time		--	80	170	nS
TD(off)	Turn-Off Delay Time		--	95	200	nS
Tf	Turn-Off Fall Time		--	55	120	nS
Qg	Total Gate Charge	$\text{VDS}=640, \text{VGS}=10\text{V}, \text{ID}=6.6\text{A}$ (Note 3,4)	--	40	52	nC
Qgs	Gate-Source Charge		--	8.5	--	nC
Qgd	Gate-Drain Charge		--	20	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	7.5	A	
I_{SM}	Maximum Plated Drain-Source Diode Forward Current	--	--	26.4	A	
V_{SD}	Drain-Source Diode Forward Voltage	$\text{Id}=6.6\text{A}$	--	--	1.4	V
trr	Reverse Recovery Time	$\text{I}_S=6.6\text{A}, \text{V}_{GS}=0\text{V}$	--	400	--	nS
Qrr	Reverse Recovery Charge	$\text{di}_F/\text{dt}=100\text{A}/\mu\text{s}$ (Note 3)	--	4.3	--	μC

*Notes 1, $L=25.0\text{mH}, \text{IAS}=6.6\text{A}, \text{VDD}=50\text{V}, \text{RG}=25\Omega$, Starting $\text{TJ}=25^\circ\text{C}$

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

4, Essentially Independent of Operating Temperature

Typical Characteristics

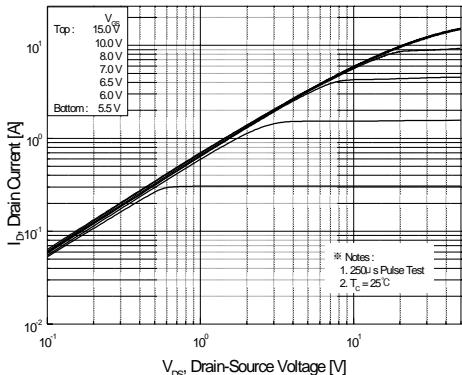


Figure 1. On-Region Characteristics

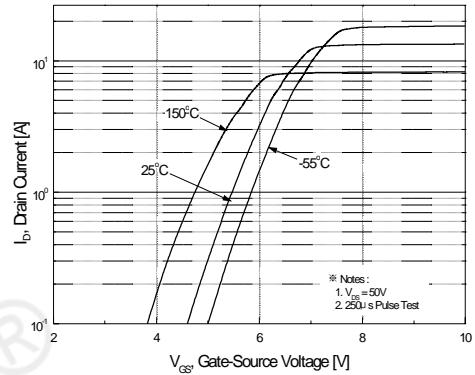


Figure 2. Transfer Characteristics

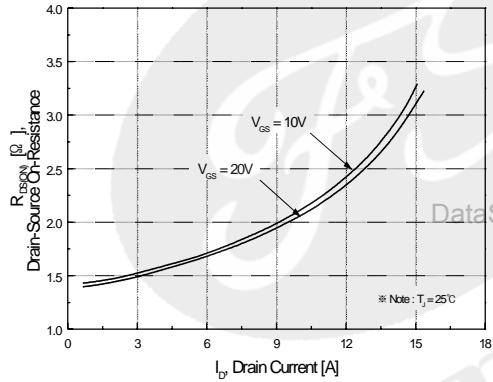


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

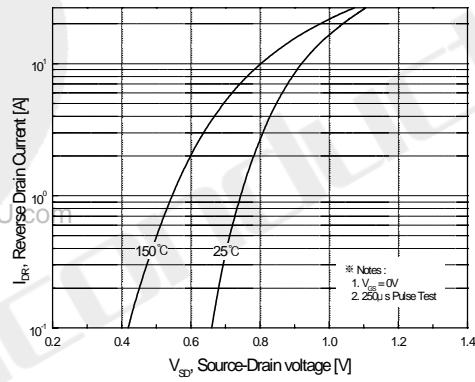


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

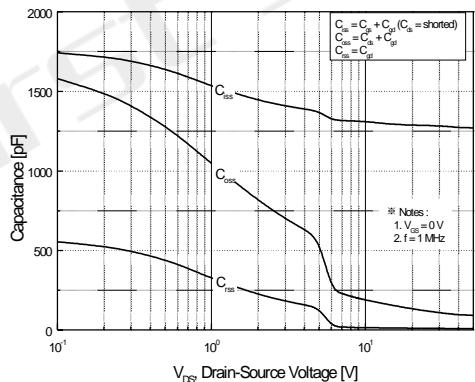


Figure 5. Capacitance Characteristics

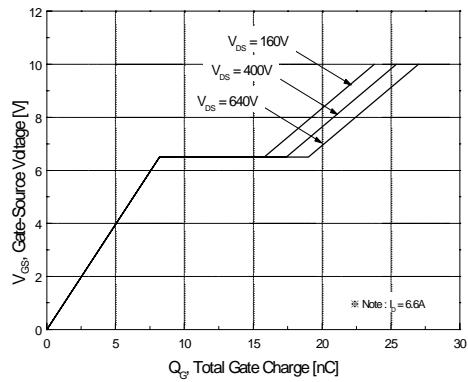


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

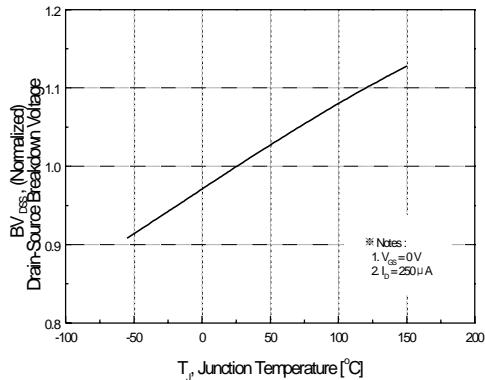


Figure 7. Breakdown Voltage Variation vs Temperature

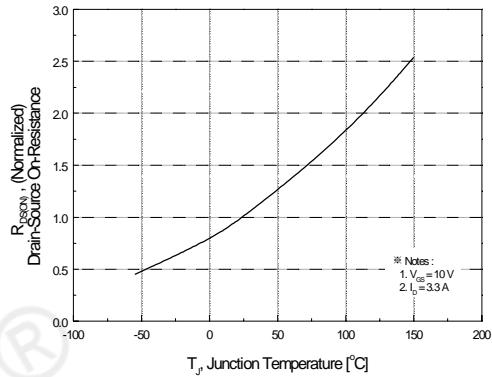


Figure 8. On-Resistance Variation vs Temperature

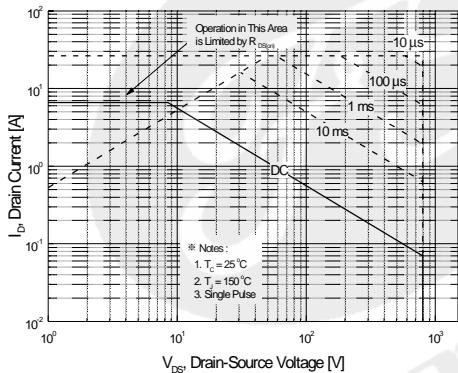


Figure 9-2. Maximum Safe Operating Area for WGF8N80

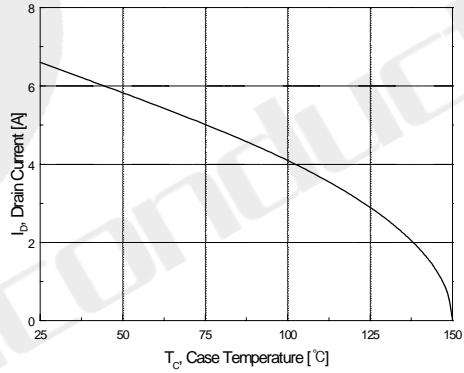


Figure 10. Maximum Drain Current vs Case Temperature

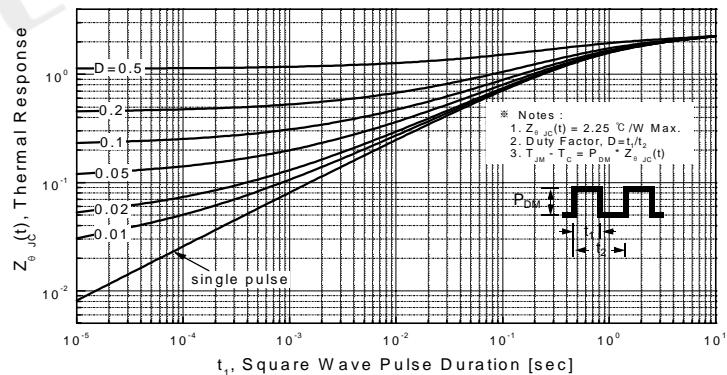
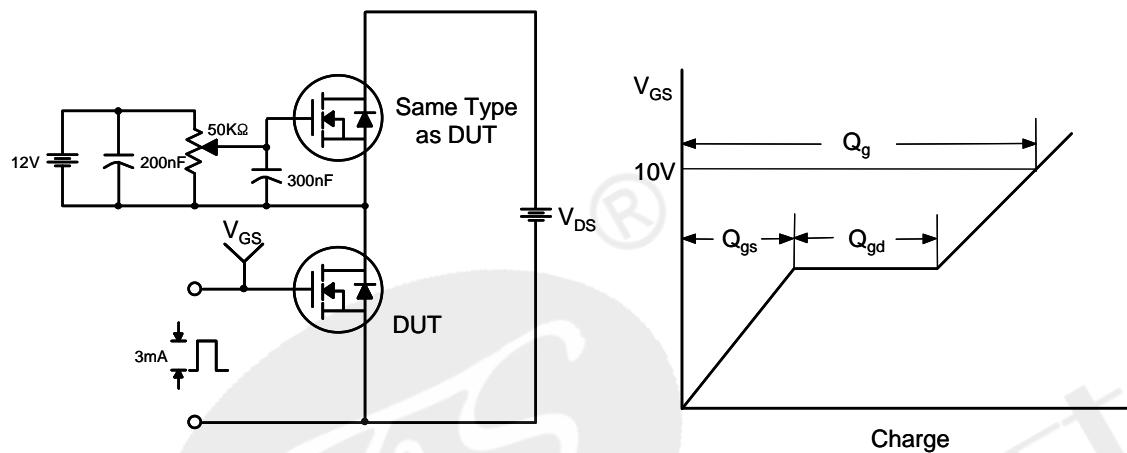
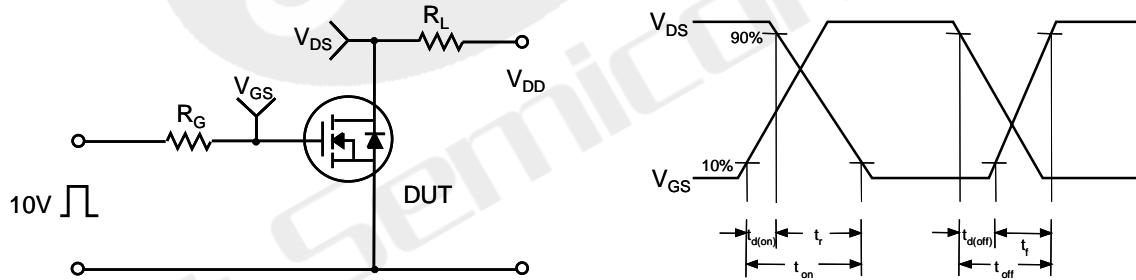
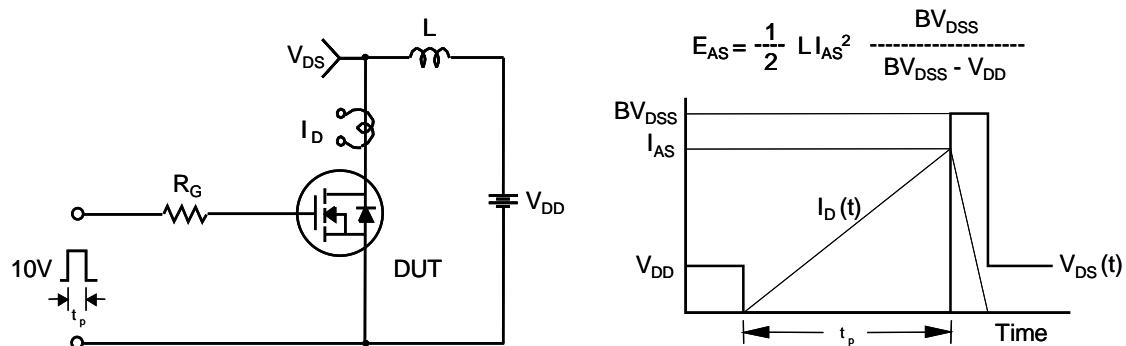
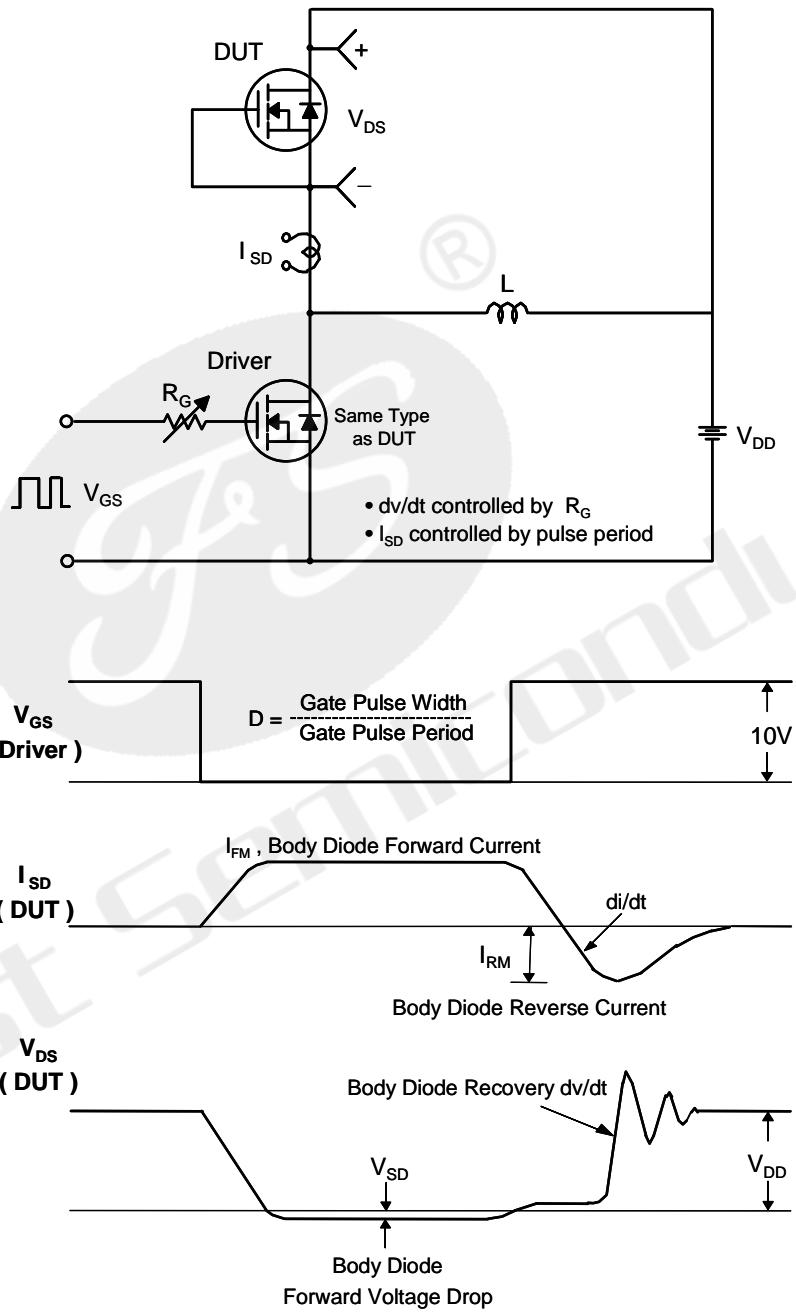


Figure 11-2. Transient Thermal Response Curve for WGF8N80

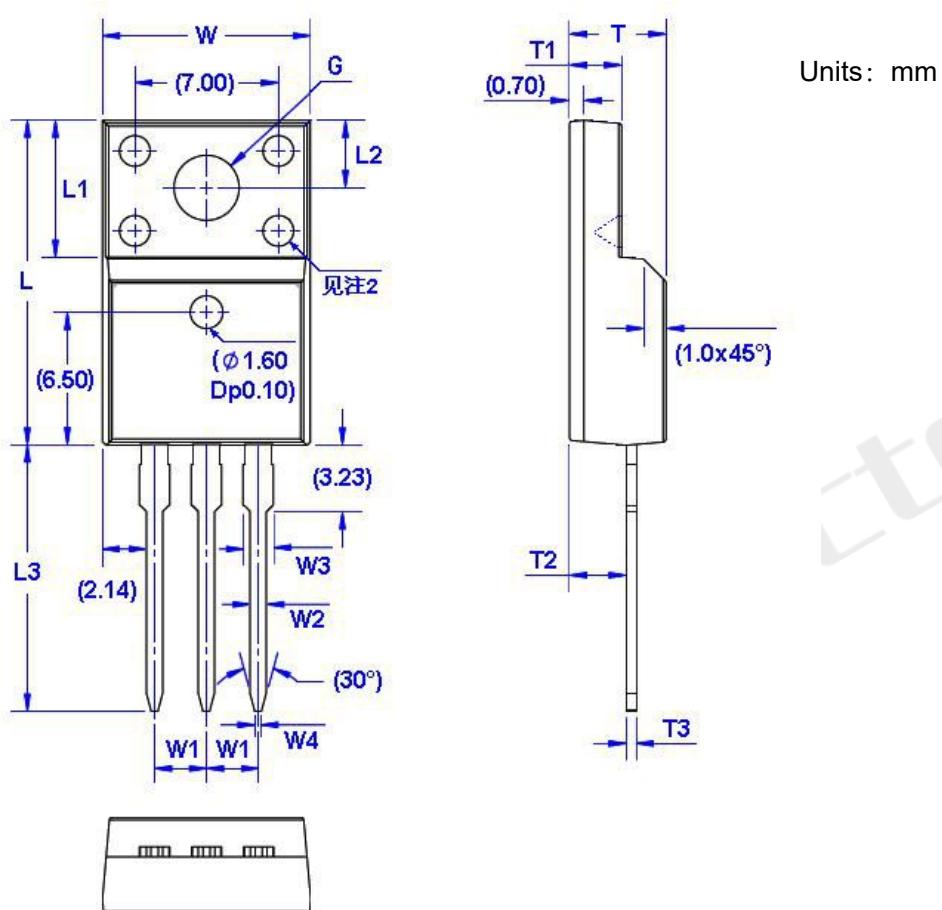
Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimension

TO-220F



Symbol	Size		Symbol	Size		Symbol	Size		Symbol	Size	
	Min	Max		Min	Max		Min	Max		Min	Max
W	9.96	10.36	W4	0.25	0.45	L3	12.78	13.18	T3	0.45	0.60
W1	2.54 (TYP)		L	15.67	16.07	T	4.50	4.90	G(Φ)	3.08	3.28
W2	0.70	0.90	L1	6.48	6.88	T1	2.34	2.74			
W3	1.24	1.47	L2	3.20	3.40	T2	2.56	2.96			



Declaration

- FIRST reserves the right to change the specifications, the same specifications of products due to different packaging line mold, the size of the appearance will be slightly different, shipped in kind, without notice! Customers should obtain the latest version information before ordering, and verify whether the relevant information is complete and up-to-date.
- Any semiconductor product under certain conditions has the possibility of failure or failure, The buyer has the responsibility to comply with safety standards and take safety measures when using FIRST products for system design and manufacturing, To avoid potential failure risks, which may cause personal injury or property damage!
- Product promotion endless, our company will wholeheartedly provide customers with better products!

ATTACHMENT

Revision History

Date	REV	Description	Page
2018.01.01	1.0	Initial release	